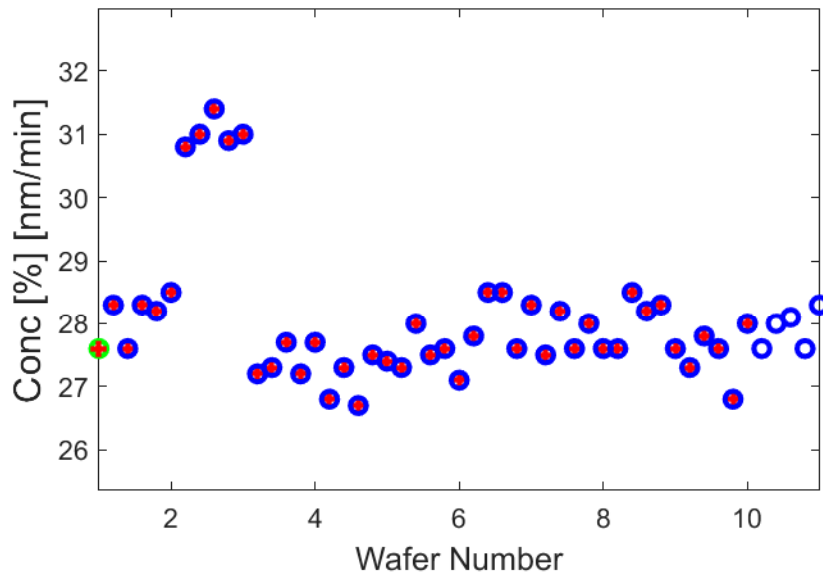
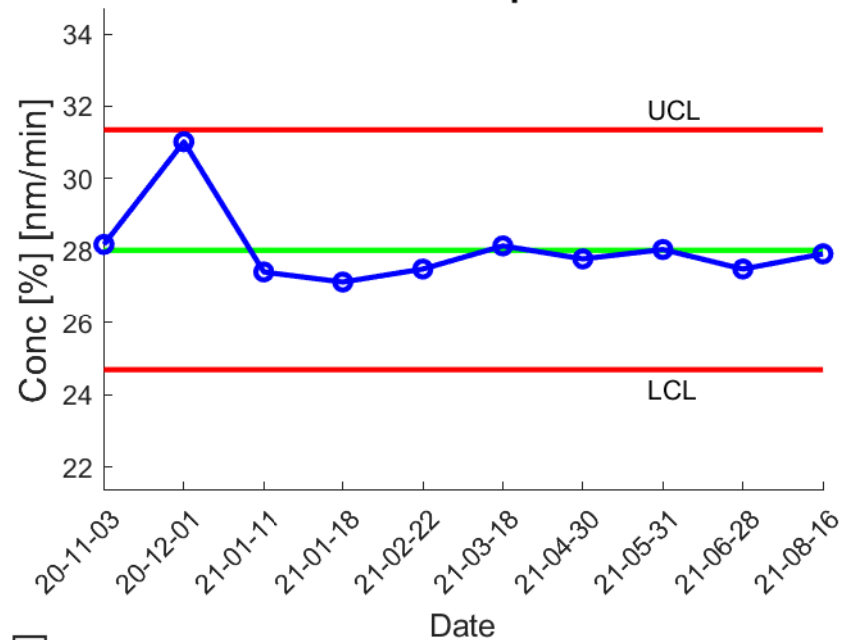


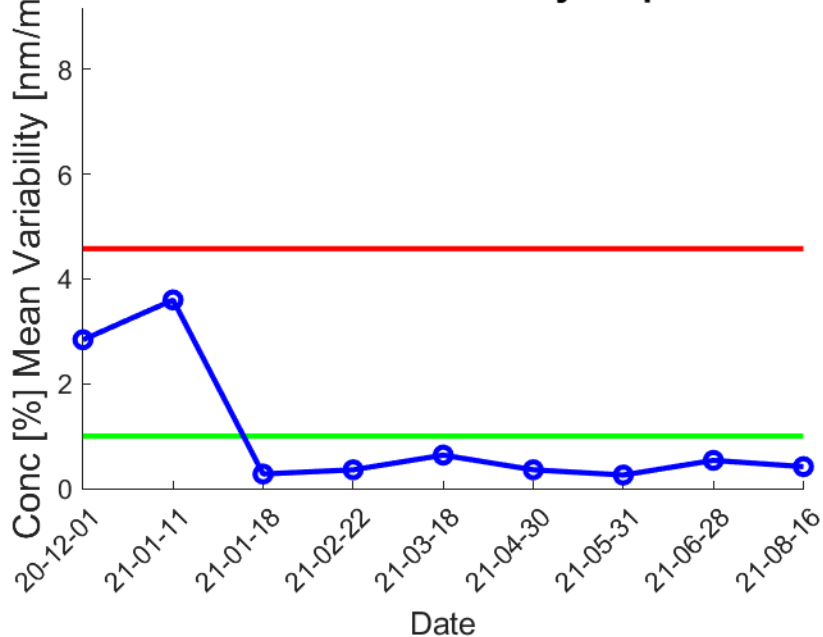
EPSILON SIGE CONC



Ge Concentration $\mu=28$ nm/min



Wafer To Wafer Variability $3\sigma/\mu < 17\%$



Within Wafer Variability $R/2\mu < 3\%$

